

 Lead Free Package and Finish

Applications:

- Switch Mode Power Supply(SMPS)
- Uninterruptible Power Supply(UPS)
- Power Factor Correction (PFC)

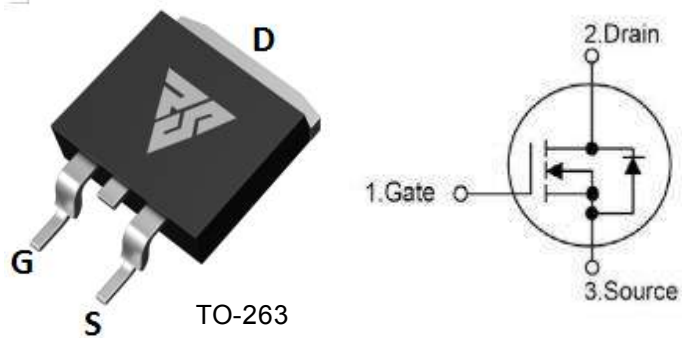
I_D	$R_{DS(ON)}(Typ)$	V_{DSS}
6A	1.7Ω	900V

Features:

- Fast switching speed
- 100% avalanche tested
- Improved dv/dt capability

Ordering Information

Part Number	Package	Marking
RS6N90S	TO-263	RS6N90S



Not to Scale

Absolute Maximum Ratings $T_c=25$ unless otherwise specified

Symbol	Parameter	RS6N90S	Units
V_{DSS}	Drain-to-Source Voltage	900	V
I_D	Continuous Drain Current	6	A
I_{DM}	Pulsed Drain Current (Note*1)	24	
PD	Power Dissipation	160	W
VGS	Gate-to-Source Voltage	±30	V
EAS	Single Pulse Avalanche Energy L=10mH VDD=50V RG=25Ω TJ=25	180	mJ
IAS	Avalanche Current (Note*1)	6	A
E_{AR}	Repetitive Avalanche Energy (Note*1)	0.72	mJ
TL TPKG	Maximum Temperature for Soldering	300	
	Leads at 0.063in(1.6mm)from Case for 10 seconds Package Body for 10 seconds		
T_J and T_{STG}	Operating Junction and Storage Temperature Range	-55 to 150	

* Drain Current Limited by Maximum Junction Temperature

Caution: Stresses greater than those listed in the "Absolute Maximum Ratings" Table may cause permanent damage to the device.

Thermal Resistance

Symbol	Parameter	RS6N90S	Units	Test Conditions
$R_{\theta JC}$	Junction-to-Case	0.78	/ W	Drain lead soldered to water cooled heatsink, PD adjusted for a peak junction temperature of +150
$R_{\theta JA}$	Junction-to-Ambient	62.5		1 cubic foot chamber, free air.

**OFF Characteristics** $T_J=25^{\circ}\text{C}$ unless otherwise specified

Symbol	Parameter	Min.	Typ.	Max.	Units	Test Conditions
BVDSS	Drain-to-source Breakdown Voltage	900	--	--	V	$V_{GS}=0V, I_D=250\mu A$
IDSS	Drain-to-Source Leakage Current	--	--	1.0	μA	$V_{DS}=900V, V_{GS}=0V$
IGSS	Gate-to-Source Forward Leakage	--	--	100	nA	$V_{GS}=+30V, V_{DS}=0V$
	Gate-to-Source Reverse Leakage	--	--	-100		$V_{GS}=-30V, V_{DS}=0V$

ON Characteristics $T_J=25^{\circ}\text{C}$ unless otherwise specified

Symbol	Parameter	Min.	Typ.	Max.	Units	Test Conditions
RDS(on)	Static Drain-to-Source On-Resistance (Note*2)	--	1.7	2.05	Ω	$V_{GS}=10V, I_D=3A$
VGS(TH)	Gate Threshold Voltage	3.0	--	4.0	V	$V_{GS}=V_{DS}, I_D=250\mu A$

Resistive Switching Characteristics Essentially independent of operating temperature

Symbol	Parameter	Min.	Typ.	Max.	Units	Test Conditions
td(ON)	Turn-on Delay Time	--	43	--	nS	$V_{DS}=450V$ $I_D=6A$ $R_G=25Q$
trise	Rise Time	--	26	--		
td(OFF)	Turn-OFF Delay Time	--	208	--		
tfall	Fall Time	--	47	--		

Dynamic Characteristics Essentially independent of operating temperature

Symbol	Parameter	Min.	Typ.	Max.	Units	Test Conditions
Ciss	Input Capacitance	--	1215	--	pF	$V_{GS}=0V$ $V_{DS}=25V$ $f=1.0MHz$
Coss	Output Capacitance	--	115	--		
Crss	Reverse Transfer Capacitance	--	21	--		
Qg	Total Gate Charge	--	48	--	nC	$V_{DS}=720V$ $I_D=6A$ $V_{GS}=15V$
Qgs	Gate-to-Source Charge	--	4.8	--		
Qgd	Gate-to-Drain("Miller") Charge	--	27	--		



Source-Drain Diode Characteristics

Symbol	Parameter	Min.	Typ.	Max.	Units	Test Conditions
I _S	Continuous Source Current	--	--	6	A	Integral pn-diode in MOSFET
I _{SM}	Maximum Pulsed Current	--	--	24	A	
V _{SD}	Diode Forward Voltage	--	--	1.4	V	I _S =3A, V _{GS} =0V
t _{rr}	Reverse Recovery Time	--	567	--	nS	V _{GS} =0V I _S =6A, di/dt=100A/μs
Q _{rr}	Reverse Recovery Charge	--	1.6	--	μC	

Notes:

*1. Repetitive rating; pulse width limited by maximum junction temperature.

*2. Pulse Test: Pulse width ≤ 300μs, Duty Cycle ≤ 1%

Typical Feature curve

Figure 1. Output Characteristics (T_J = 25°C)

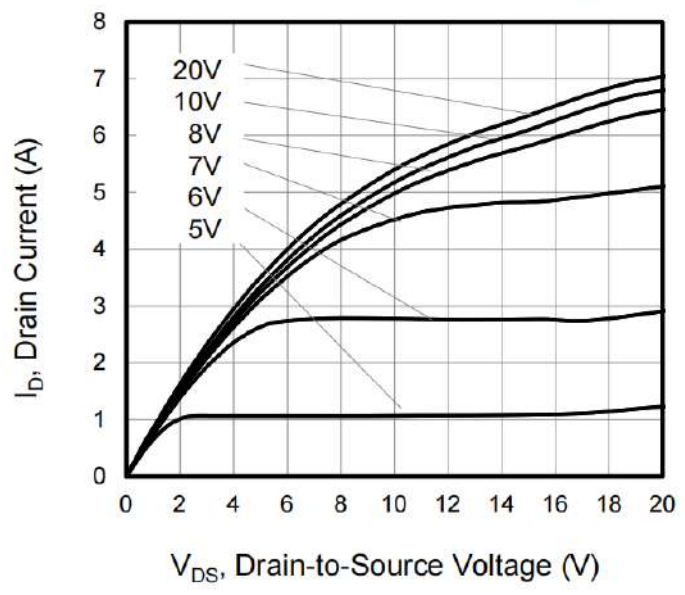


Figure 2. Body Diode Forward Voltage

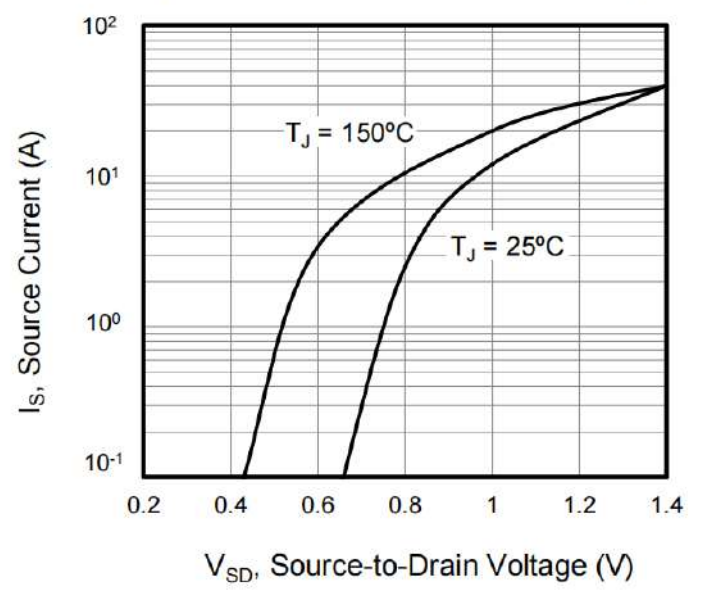


Figure 3. Drain Current vs. Temperature

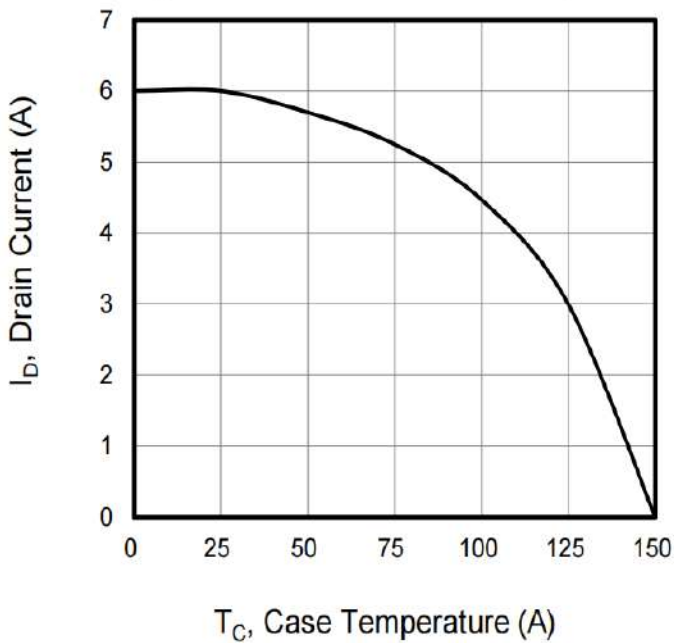


Figure 4. BV_{DSS} Variation vs. Temperature

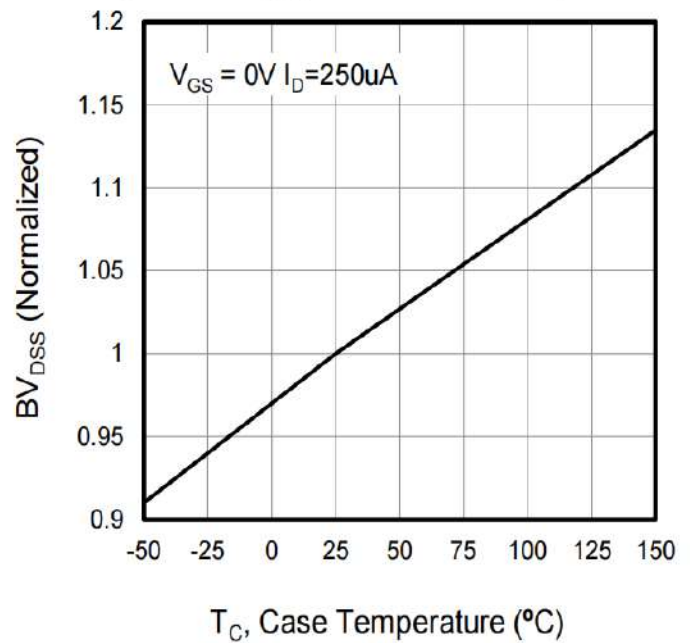


Figure 5. Transfer Characteristics

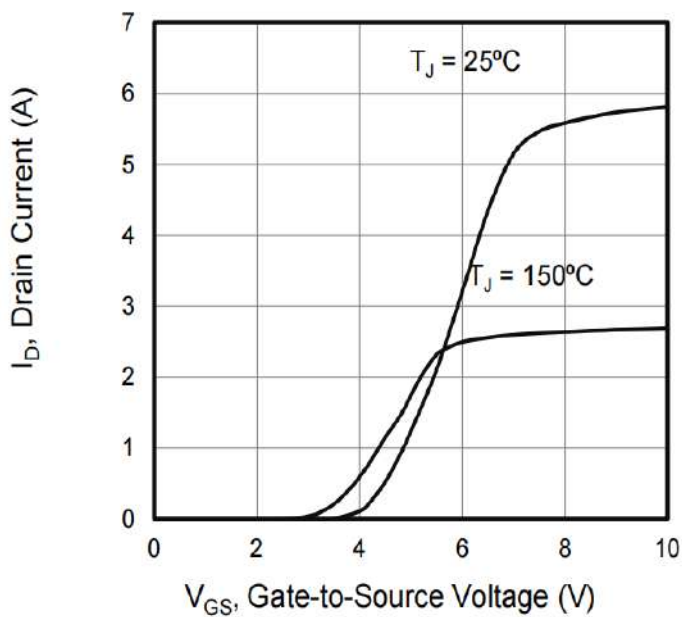


Figure 6. On-Resistance vs. Temperature

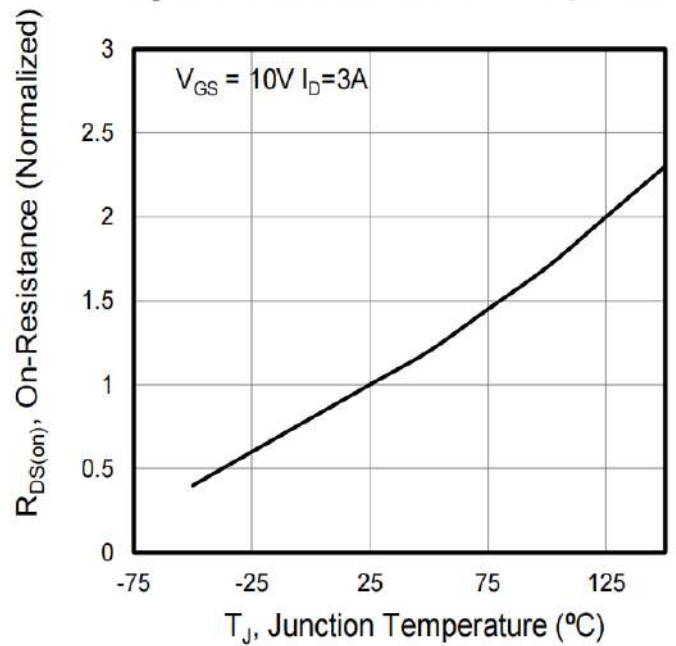


Figure 7. Capacitance

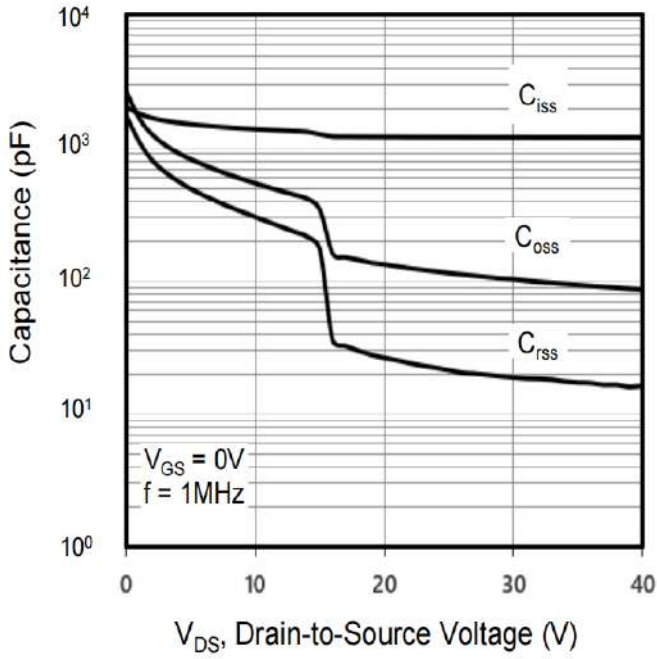


Figure 8. Gate Charge

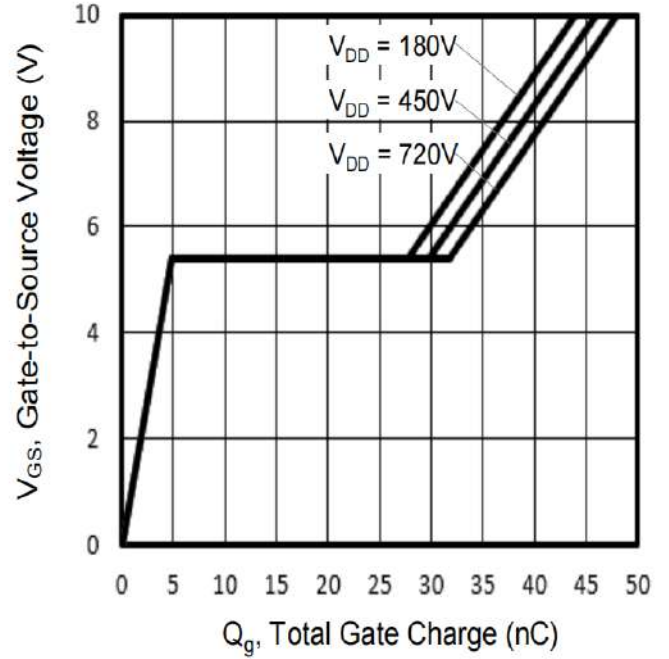
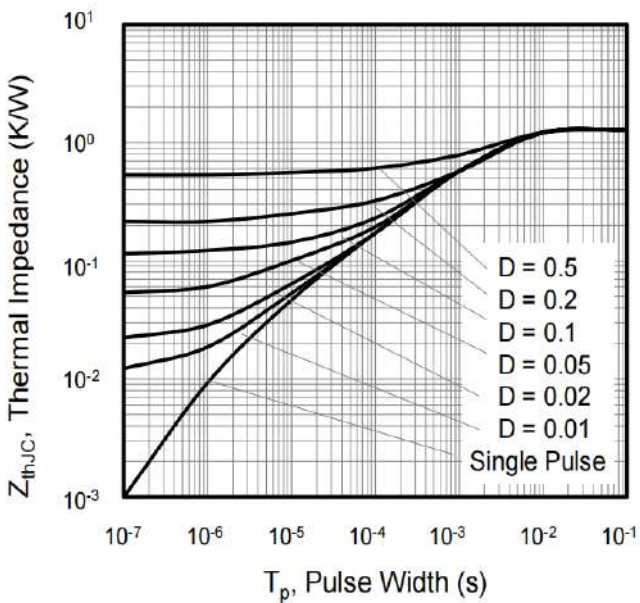


Figure 9. Transient Thermal Impedance



Test Circuits and Waveforms

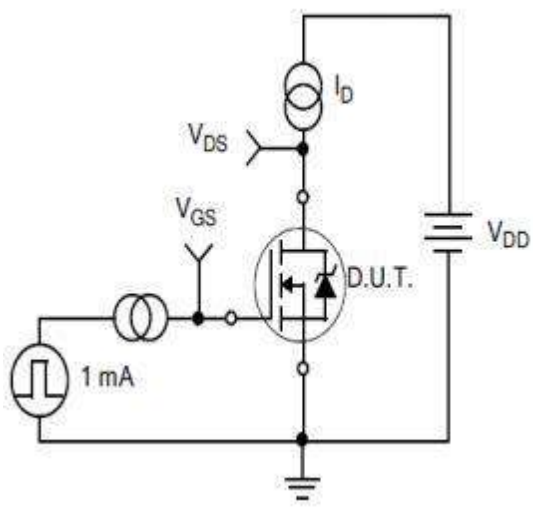


Figure A.
Gate Charge Test Circuit

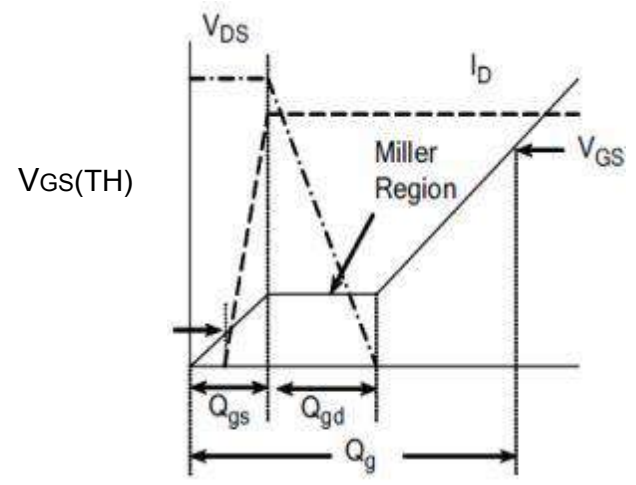


Figure B.
Gate Charge Waveform

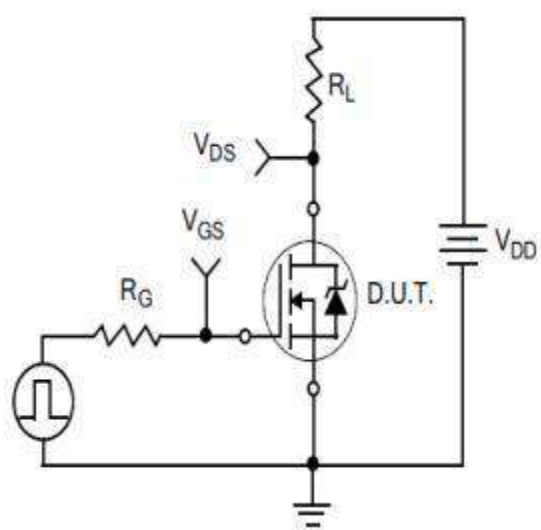


Figure C.
Resistive Switching Test Circuit

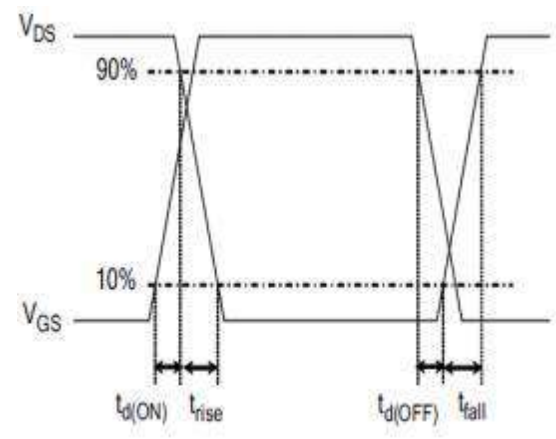


Figure D.
Resistive Switching Waveforms

Test Circuits and Waveforms

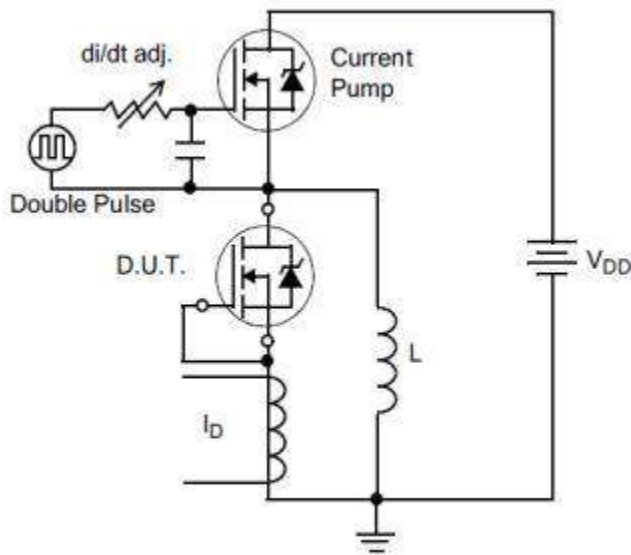


Figure E. Diode Reverse Recovery Test Circuit

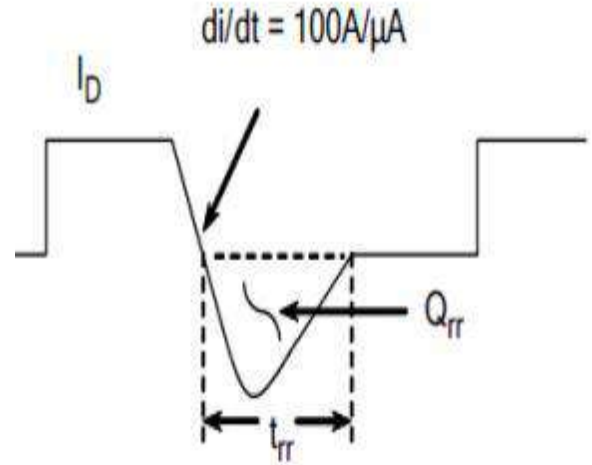


Figure F. Diode Reverse Recovery Waveform

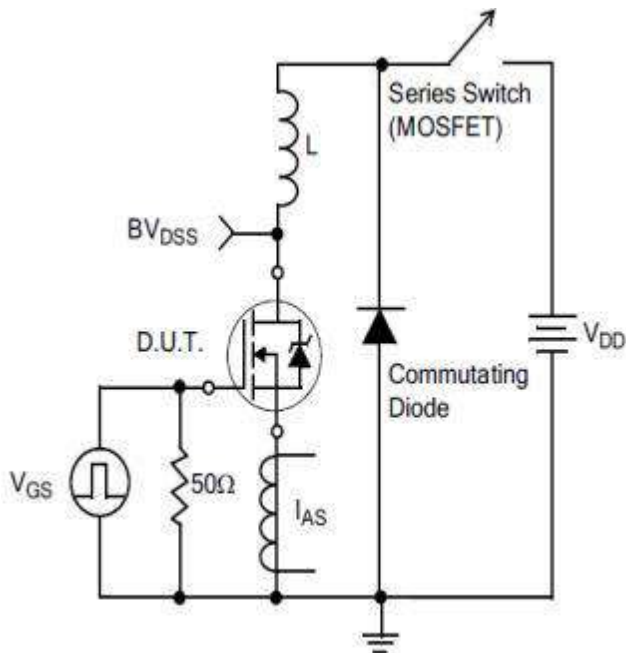
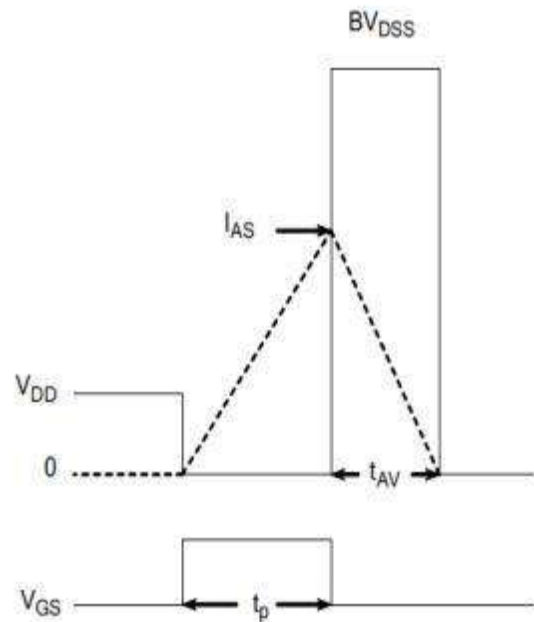


Figure G. Unclamped Inductive Switching Test Circuit



$$E_{AS} = \frac{I_{AS}^2 L}{2}$$

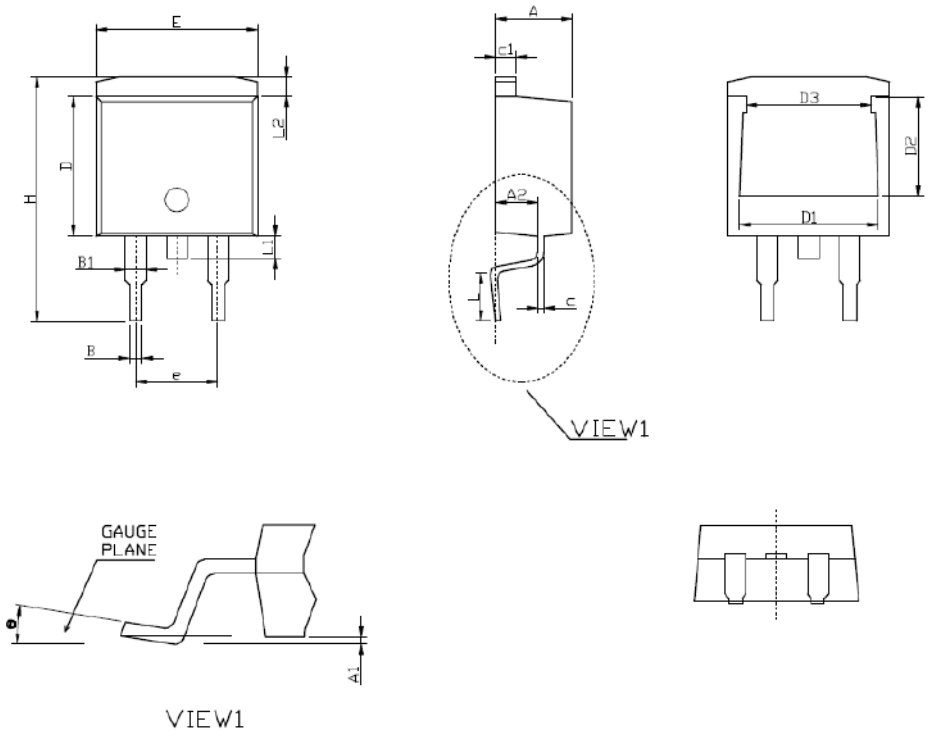
Figure H. Unclamped Inductive Switching Waveforms



Package outline drawing

TO-263

Unit:mm



SYMBOLS	MILLIMETERS	
	MIN	MAX
A	4.40	4.90
A1	0.05	0.30
A2	2.40	2.80
B	0.72	0.92
B1	1.12	1.45
c	0.28	0.48
c1	1.17	1.37
D	8.46	8.86
D1	7.90	8.40
D2	5.50	5.90
D3	7.10	7.50
E	9.85	10.45
e	5.08BCS	
H	14.75	15.55
L	2.30	2.80
L1	1.20	1.60
L2	1.01	1.50



Disclaimers:

Reasunos Semiconductor Technology CO.,LTD(Reasunos)reserves the right to make changes without notice in order to improve reliability,function or design and to discontinue any product or service without notice .Customers should obtain the latest relevant information before orders and should verify that such information in current and complete.All products are sold subject to Reasunos's terms and conditions supplied at the time of order acknowledgement.

Reasunos Semiconductor Technology CO.,LTD warrants performance of its hardware products to the specifications at the time of sale.Testing,reliability and quality control are used to the extene Reasunos deems necessary to support this warrantee. Except where agreed upon by contractual agreement,testing of all parameters of each product is not necessarily performed.

Reasunos Semiconductor Technology CO.,LTD does not assume any liability arising from the use of any product or circuit designs described herein.Customers are responsible for their products and applications using Reasunos's components.To minimize risk,customers must provide adequate design and operating safeguards.

Reasunos Semiconductor Technology CO.,LTD does not warrant or convey any license either expressed or implied under its patent rights,nor the rights of others.Reproduction of information in Reasunos's data sheeets or data books is permissible only if reproduction is without modification oralteration.Reproduction of this information with any alteration is an unfair and deceptive business practice. Reasunos Semiconductor Technology CO.,LTD is not responsible or liable for such altered documentation.

Resale of Reasunos's products with statements different from or beyond the parameters stated by Reasunos Semiconductor Technology CO.,LTD for that product or service voids all express or implied warranties for the associated Reasunos's product or service and is unfair and deceptive business practice. Reasunos Semiconductor Technology CO.,LTD is not responsible or liable for such statements.

Life Support Policy:

Reasunos Semiconductor Technology CO.,LTD's Products are not authorized for use as critical components in life support devices or systems without the expressed written approval of Reasunos Semiconductor Technology CO.,LTD.

As used herein:

- 1.Life support devices or systems are devices or systems which:
 - a.are intended for surgical implant into the human body,
 - b.support or sustain life,
 - c.whose failuer to when properly used in accordance with instructions for used provided in the laeling,can be reasonably expected to result in significant injury to the user.

 - 2.A critical component is any component of a life support device or system whose failure to system whose failure to perform can be reasonably expected to cause the failure of the life support device or system,or to affect its safety or effectiveness.
-